

BEST AVAILABLE COPY PATENT ABSTRACTS OF JAPAN

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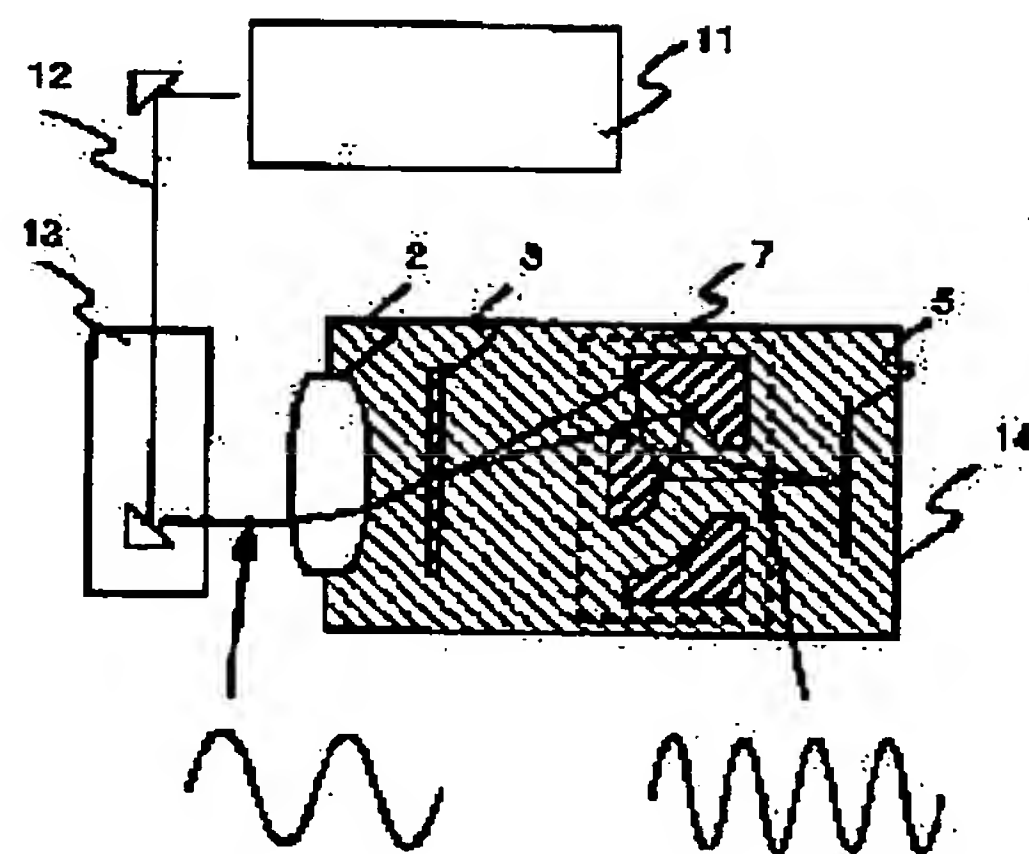
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(54) PATTERN FORMING METHOD AND EXPOSURE APPARATUS THEREFOR

(57)Abstract:

PURPOSE: To improve resolution by forming a projection optical system of an optical system having a reflection type lens, and fully filling entirety or part of an optical path of the projection system included between a surface of a board and the projection system with medium having 1 or more of specific refractive index to the air in the wavelength of a light.

CONSTITUTION: A beam 12 generated from a KrF excimer laser 11 is emitted to a mask 3 via a beam shaping optical system 13 and an illumination optical system 2. A light passing through the mask 3 is exposed on a board 5 via a reflection type contraction projection lens 7. The lens 7 is a Schwarzschild type optical system having a numerical aperture of 0.3 to focus the mask 3 on the board 5. The entire system from the irradiating side of the illumination system to the board via the mask is installed in a liquid vessel 14, and water is fully filled in the vessel to fill the water in the optical path. Then, a pattern is transferred to a positive resist film coating the Si board by using a projection exposure apparatus to form a 0.35 μ mL/S pattern.



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CLAIMS

[Claim(s)]

[Claim 1] In the approach of forming a pattern on the above-mentioned substrate by irradiating at a mask the light which emitted the light source through an illumination-light study system, and carrying out image formation of the pattern on the above-mentioned mask to up to a substrate according to projection optics The pattern formation approach characterized by filling with a medium with the bigger rate of specific refraction to the air in the wavelength of the above-mentioned light than 1 the whole optical path or a part of the above-mentioned projection optics which constitutes the above-mentioned projection optics according to the optical system containing a reflective mold lens, and includes between the above-mentioned substrate and the above-mentioned projection optics at least.

[Claim 2] It is the pattern formation approach that the above-mentioned medium is a liquid in claim 1.

[Claim 3] It is the pattern formation approach that the wavelength of the above-mentioned light is 150-250nm in claim 2.

[Claim 4] In the aligner used in case a pattern is formed on the above-mentioned substrate by irradiating at a mask the light which emitted the light source through an illumination-light study system, and carrying out image formation of the pattern on the above-mentioned mask to up to a substrate according to projection optics The projection aligner characterized by filling with a medium with the bigger rate of specific refraction to the air in the wavelength of the above-mentioned light than 1 the whole optical path or a part of the above-mentioned projection optics which constitutes the above-mentioned projection optics according to the optical system containing a reflective mold lens, and includes between the above-mentioned substrate and the above-mentioned projection optics.

[Claim 5] The projection aligner which forms a transparent septum between the above-mentioned projection optics and said substrate, and divides the above-mentioned medium into an optical-system and substrate side in claim 4.

[Translation done.]

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DETAILED DESCRIPTION

[Detailed Description of the Invention]

[0001]

[Industrial Application] This invention relates to the pattern formation approach for forming the detailed pattern of various solid-state components, and the projection aligner used for this.

[0002]

[Description of the Prior Art] In order to improve the degree of integration and working speeds of a solid-state component, such as LSI, detailed-ization of a circuit pattern is progressing. The reduced-projection-exposure method excellent in mass-production nature and definition ability is widely used for such pattern formation now.

[0003] The optical system of a reduced-projection-exposure method is typically shown in drawing 2 (b). The light which emitted the effective light source 1 on a secondary surface of light source is irradiated by the mask 3 through the illumination-light study system 2, and image formation of the light diffracted with the pattern on a mask 3 is carried out on a substrate 5 with the contraction projection lens 4. What a contraction projection lens usually becomes from the combination of a refraction mold lens is used. Since the resolution limit of this approach is proportional to exposure wavelength and it is in inverse proportion to the numerical aperture (NA) of a projection lens, improvement in the resolution limit has been performed by a raise in NA, and short wavelength-ization. Conventionally, after 64-megabit DRAM, the circuit dimension became smaller than the wavelength of light, and exposure light has reached the physical limitation, although g line (wavelength of 436nm) of a high-pressure mercury lamp and i line (wavelength of 365nm) have been used.

[0004] as the approach of on the other hand increasing effectual NA of the optical system of a microscope etc. -- immersion (oil immersion) -- law is known. By being filled up with the liquid (an oil usually being used) which has the bigger refractive index n than air between the tip of a lens, and a sample, this approach sets wavelength of light to $1/n$ effectually, and raises resolution. The application to the optical lithography of this approach is discussed by for example, the collection of the 53rd Japan Society of Applied Physics academic lecture meeting lecture drafts, the 2nd separate volume, and the 472nd page (1992).

[0005] On the other hand, the approach using reflective mold projection optics, such as a step and a scanning method, as another gestalt of the projection aligner for optical lithographies is examined. It is not based on wavelength but this optical system is a maximum of 0.7. To NA with big extent, implementation is made possible and it is very promising as a future aligner. In this method, although a refraction mold optical element is used for a part, since chromatic-aberration amendment is possible, it exposes in the comparatively large wavelength field of 245-253nm of a xenon mercury lamp. For this reason, stabilization of wavelength is not needed by any means with narrow-band-ization of a precise laser wavelength spectrum like a excimer laser stepper using the conventional full refraction mold optical system, and multiplex cross protection and the standing wave effectiveness can be reduced. Moreover, it is the practical big features that exposure area is also large.

[0006] The optical system of a step and a scanning method is discussed by the 14th page from the 12th page (TECHNICAL INFORMATION INSTITUTE, Tokyo, 1991) of a resist ingredient process technique.

[0007]

[Problem(s) to be Solved by the Invention] By the way, refraction mold objective lenses, such as a microscope used with the above-mentioned conventional immersion method, are designed by dedication on the assumption that it is filled up with the liquid of a predetermined refractive index between a lens tip and a sample. The same of this situation is said of the case of the lens for projection exposure, and it is necessary to design the projection lens corresponding to immersion specially as an exclusive lens with a design which is completely conventionally different from a lens. Here, suppose that the liquid restoration field 6 (drawing

2 (b) shadow area) between the tip of conventional-type dioptric lenses other than for immersion and a substrate (or sample) was temporarily filled up with the liquid of a refractive index n . In this case, although wavelength is effectually set to $1/n$, in order that the angle of refraction in a lens tip may decrease according to a Snell's law, the optical path of a beam of light changes like the broken line of drawing 2 (b), and effectual NA decreases. For this reason, resolution does not necessarily improve. And there was a problem that it was very difficult to reconcile with big NA peculiar to an immersion lens a large exposure area demanded in the lens for steppers.

[0008] It is desirable to shorten exposure wavelength as much as possible on the other hand, in order to improve the resolution of optical lithography further. However, both the exposing method by conventional-type dioptric system and the reflective mold projection exposing method had the problem that ArF excimer laser (wavelength of 193nm) will become the limitation of practical short-wavelength-izing from the limitation of the permeability of an optical material.

[0009] It is to offer the pattern formation approach which can be improved to a limit in the resolution of the projection exposing method, the purpose of this invention acquiring the improvement effectiveness in resolution equivalent to having short-wavelength-ized effectually simple, and securing a large exposure field, without changing greatly the configuration and optical system of an aligner of a conventional type.

[0010]

[Means for Solving the Problem] In the approach of forming a pattern on the above-mentioned substrate by this invention's irradiating at a mask the light which emitted the light source through an illumination-light study system, and carrying out image formation of the pattern on the above-mentioned mask to up to a substrate according to projection optics, in order to attain the above-mentioned purpose The optical system containing a reflective mold lens constitutes the above-mentioned projection optics, and the whole optical path or a part of the above-mentioned projection optics which includes between the above-mentioned substrate and the above-mentioned projection optics at least is filled with a medium with the bigger rate of specific refraction to the air in the wavelength of the above-mentioned light than 1.

[0011]

[Function] It considers changing the refractive index of the medium which fulfills the whole optical path of the catoptric system shown in drawing 2 (a). Drawing 2 (a) transposes the refraction mold contraction projection lens 4 in drawing 2 (b) to the reflective mold contraction projection lens 7. In drawing 2 (a), the continuous line and the dotted line showed respectively the optical path of a beam of light when the refractive index of a medium is small, and the optical path of the beam of light in the case of being large. The optical path in catoptric system is decided only by the shape of surface type of a reflective lens according to the law of reflection, and is not based on the refractive index of a medium. Therefore, even if it changes the refractive index of a medium, the geometrical optics-property of optical system, such as numerical aperture, does not change at all. On the other hand, if the matter of the rate n of specific refraction to a vacuum is used as a medium, wavelength will be effectually set to $1/n$. Consequently, effectiveness equal to only wavelength having become short substantially is acquired. in addition -- although perfect catoptric system was assumed and explained by drawing 2 R> 2 (a) since it was easy -- partial -- dioptric system -- business -- a potato is good.

[0012] Moreover, a medium is 1.2, in order that it may be desirable for the refractive index to exposure wavelength to be large as much as possible and it may acquire sufficient resolution effectiveness. It is desirable that it is above. Moreover, it is substantially transparent to exposure wavelength, and it is desirable not to have a bad influence on an optical element and a resist. Specifically, organic solvents, such as water or alcohol, and a straight chain hydrocarbon, silicone resin, the liquid that dissolved the inorganic compound or the organic compound in these further, the various liquids currently conventionally used in an immersion microscope, the immersion method of determination of index of refraction, etc. can be used.

[0013] In addition, since there is a possibility of having a bad influence on the image formation property of optical system when a refractive index changes with fluctuation of the temperature of a medium, a consistency, etc. in optical system, as for these temperature etc., controlling carefully is desirable. Since a substrate is especially scanned to optical system by scan optical system, it is desirable to take care so that an image formation property may not change with the flow of a medium.

[0014]

[Example]

(Example 1) The reflective mold projection aligner by one example of this invention is shown in drawing 1. The laser beam 12 generated from the KrF excimer laser 11 is irradiated at a mask 3 through the beam plastic surgery optical system 13 and the illumination-light study system 2. The light which passed the mask

exposes a substrate 5 through the reflective mold contraction projection lens 7. Reflective mold reducing glass is a numerical aperture 0.3. By the Schwartz SHURUDO mold optical system, image formation of the mask 3 is carried out on a substrate 5. However, the optical system in drawing is typical strictly, and is not what showed the configuration of actual optical system faithfully. Here, the whole optical system from the injection side of an illumination-light study system to a substrate through a mask was installed in the interior of a liquid container 14, and into the liquid container, water was filled and it was filled up with the optical path with water.

[0015] Next, it is 0.35micromL/S as a result of imprinting the pattern of various dimensions using a projection aligner on the positive-resist film (PMMA, 1 micrometer of thickness) applied on Si substrate. The pattern has been formed. For the comparison, when water was removed from optical system and having been exposed in air, the resolution limit retreated to 0.5 micrometers.

[0016] In addition, the method of the wavelength of an aligner, the class of light source, and a projection lens and a numerical aperture, the class of medium, the resist process to be used, a mask pattern dimension, etc. are not limited to what was shown in this example. For example, a high-pressure mercury lamp and a xenon mercury lamp may be used instead of excimer laser. Moreover, into a liquid solution, it may replace with water and a perfluoroalkyl polyether etc. may be used. While this liquid was transparent on exposure wavelength, the sensitization property of a resist was not affected at all. Moreover, it may replace with PMMA also as a resist and a suitable novolak system positive resist, a chemistry multiplier system resist, etc. may be used.

[0017] (Example 2) The reflective mold projection aligner by the second example of this invention is shown in drawing 3. The laser beam generated from ArF excimer laser (not shown) is irradiated at a mask 3 through beam plastic surgery optical system and an illumination-light study system (not shown). The light which passed the mask exposes a substrate 5 through the scanning catoptric system 21. Scanning catoptric system is numerical aperture 0.7. It is a step and scanning mold optical system, and image formation of the mask 3 is carried out on a substrate 5. However, the optical system in drawing is typical strictly, and is not what showed the configuration of actual optical system faithfully. Here, the field 22 shown with the slash in drawing within the optical path of projection optics was filled up with water.

[0018] Next, it is 0.11micromL/S as a result of imprinting the pattern of various dimensions using a projection aligner on the positive-resist film (PMMA, 1 micrometer of thickness) applied on Si substrate. The pattern has been formed. The resolution limit is 0.15 micrometers, when water was removed from optical system and it exposed in air for the comparison. It retreated and the effectiveness of this invention was checked.

[0019] (Example 3) In the projection aligner of an example 2, as shown in drawing 4, the parallel plate 31 of a quartz divided the optical-system and substrate side. In order that the flow of the liquid medium produced when a substrate is scanned to optical system or a step feed is carried out by this might not attain to an optical-system side, the effect of fluctuation etc. of a refractive index was suppressed and the dimensional accuracy of a pattern improved. In addition, to the spherical aberration generated by quartz aperture insertion, it amended beforehand.

[0020] (Example 4) In the projection aligner of an example 2, as shown in drawing 5, the quartz parallel plates 32 and 33 were formed between optical system and a substrate, and the liquid container was divided into the optical-system side liquid container 34 and the substrate side liquid container 35. Furthermore, it was made to perform the scan or step feed to the optical system of a substrate 5 the whole substrate side liquid container 35. Thereby, since the liquid flow near the substrate was also controlled, the effect of fluctuation etc. of a refractive index was suppressed and the dimensional accuracy of a pattern improved further.

[0021] In addition, when applying the configuration by this example to an example 1, the same device also as a mask side can be established.

[0022]

[Effect of the Invention] In case a pattern is imprinted on the above-mentioned substrate by carrying out image formation of the mask pattern to up to a substrate according to projection optics according to this invention, while the optical system containing a reflective mold lens constitutes projection optics By filling the whole optical path or a part of projection optics including between a substrate front face and projection optics with a medium with the bigger rate of specific refraction to the air in the wavelength of light than 1 Improvement in resolution equivalent to having short-wavelength-ized effectually simple can be aimed at without changing greatly the configuration and optical system of an aligner of a conventional type. Thereby, the resolution limit of optical lithography is improved about 30%, and it is 0.15 micrometers. It becomes

possible to form the following patterns.

[Translation done.]

* NOTICES *

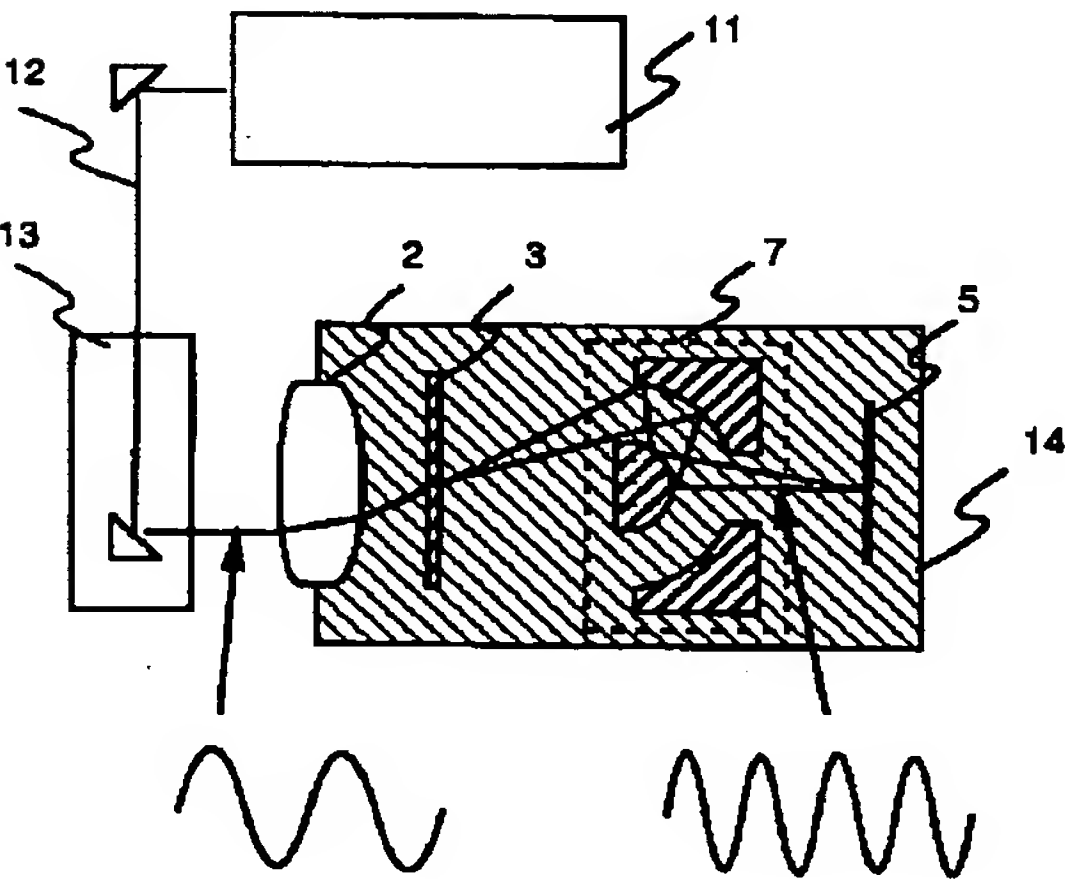
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DRAWINGS

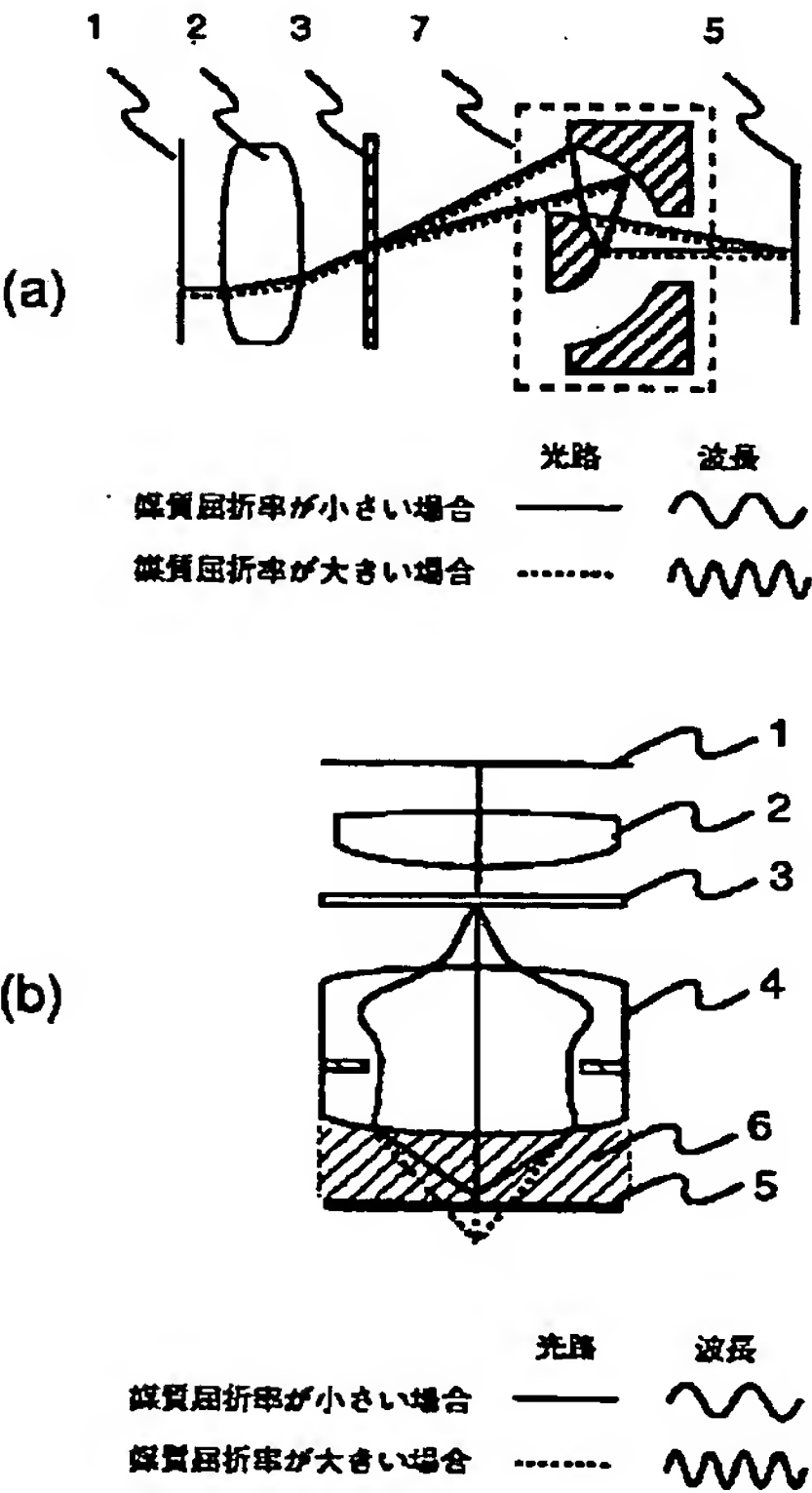
[Drawing 1]

図 1



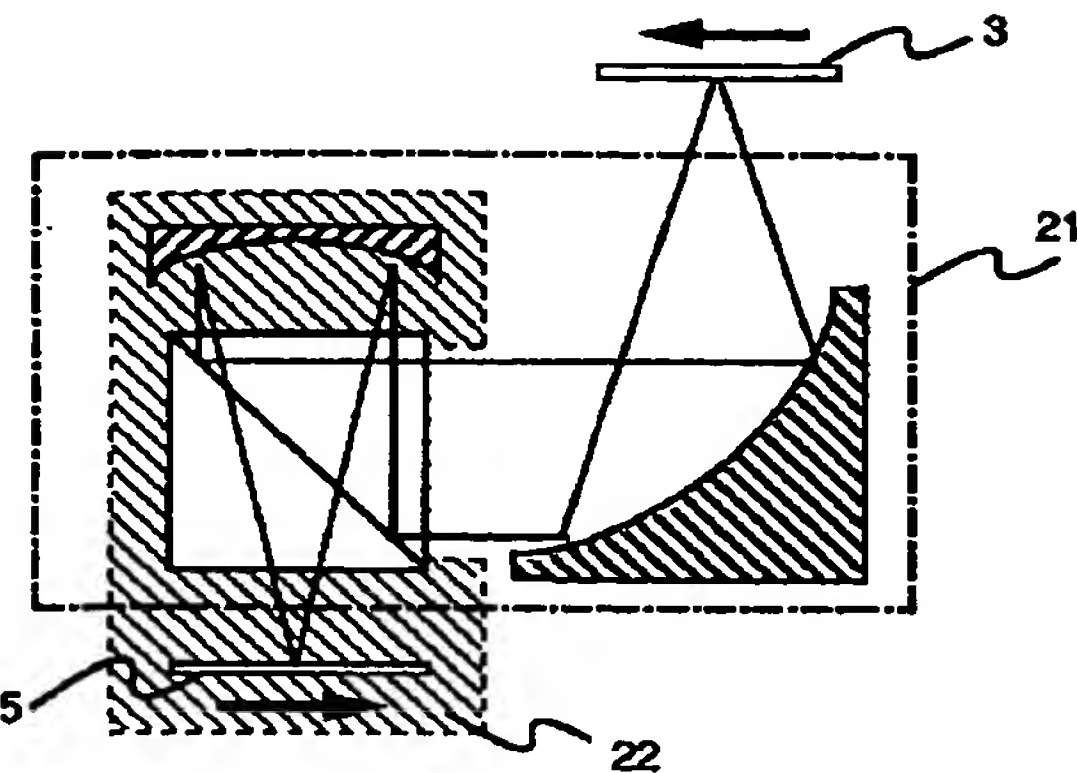
[Drawing 2]

図 2



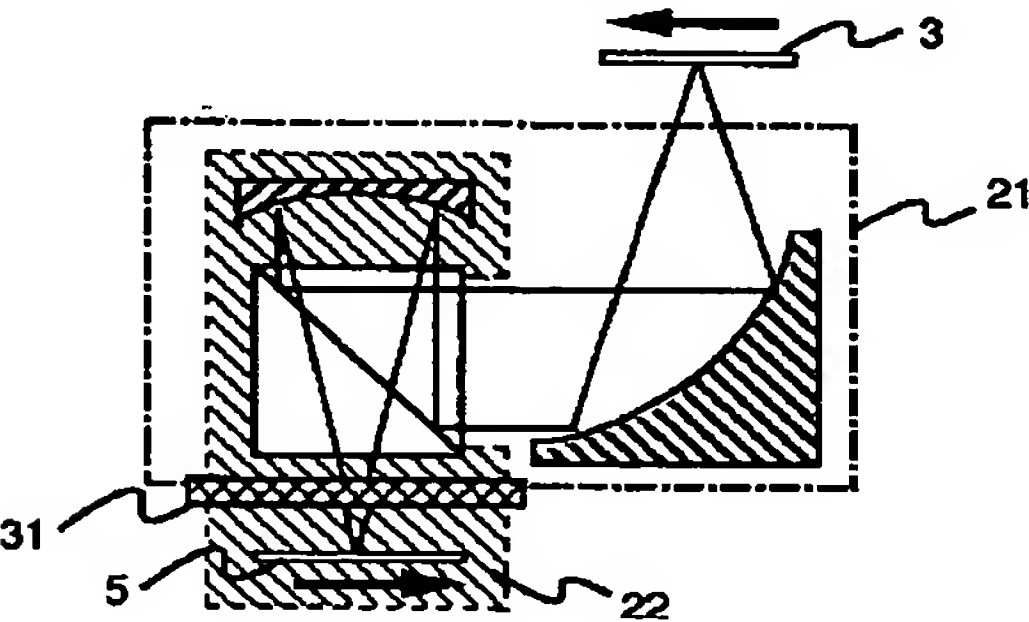
[Drawing 3]

図 3



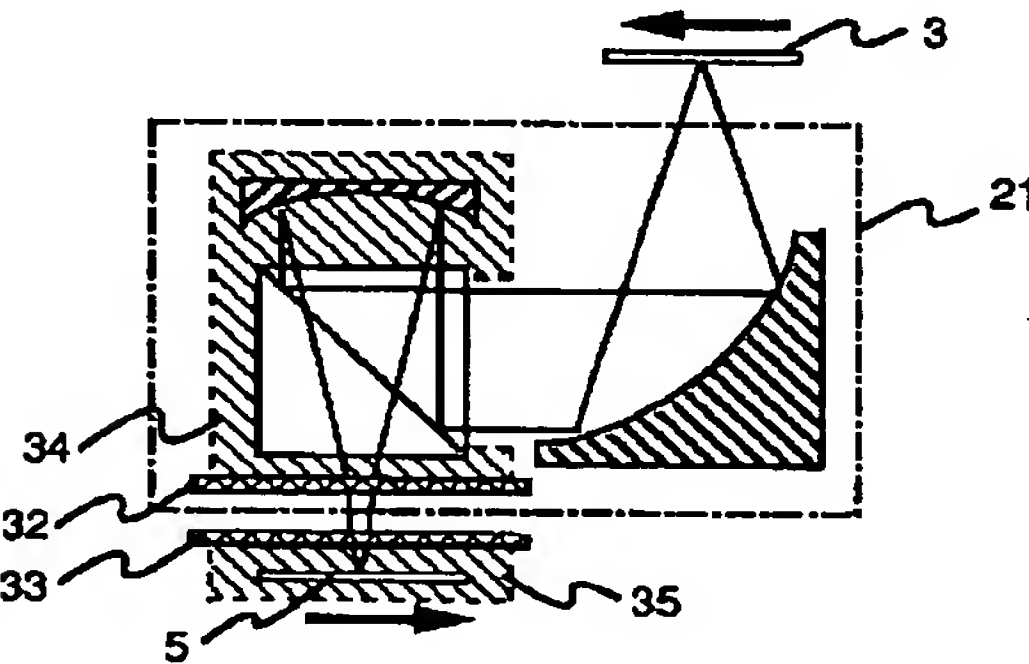
[Drawing 4]

図 4



[Drawing 5]

図 5



[Translation done.]

(19)



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(72) Inventor: **FUKUDA HIROSHI**
TANAKA TOSHIHIKO

(54) **PATTERN FORMING METHOD AND EXPOSURE APPARATUS THEREFOR**

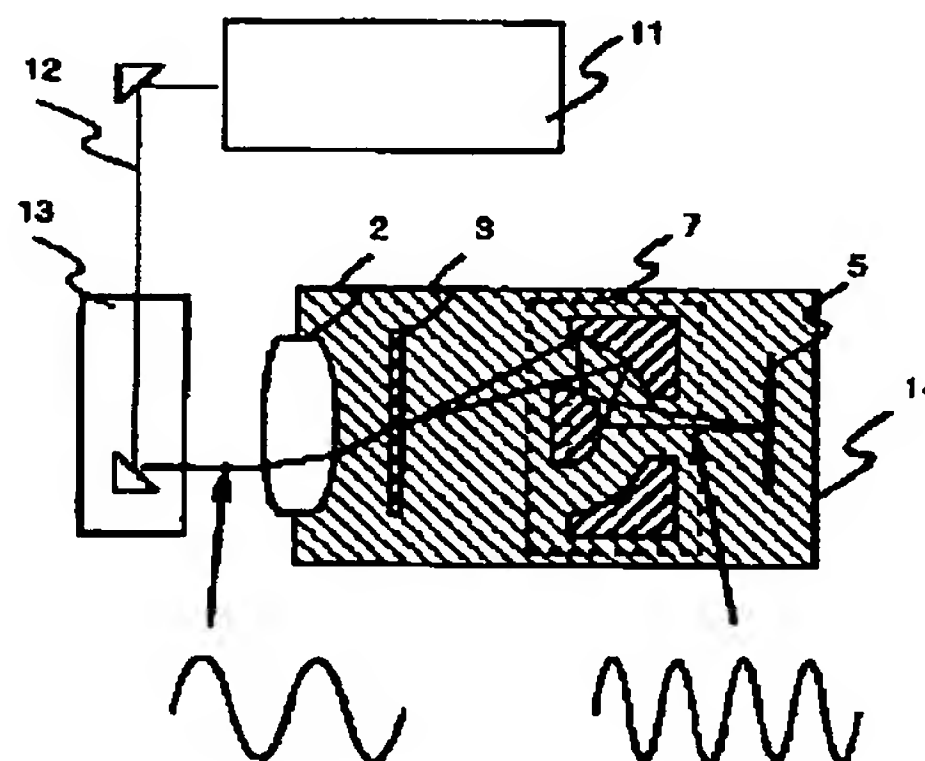
0.35 μ m/L/S pattern.

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(57) Abstract:

PURPOSE: To improve resolution by forming a projection optical system of an optical system having a reflection type lens, and fully filling entirety or part of an optical path of the projection system included between a surface of a board and the projection system with medium having 1 or more of specific refractive index to the air in the wavelength of a light.

CONSTITUTION: A beam 12 generated from a KrF excimer laser 11 is emitted to a mask 3 via a beam shaping optical system 13 and an illumination optical system 2. A light passing through the mask 3 is exposed on a board 5 via a reflection type contraction projection lens 7. The lens 7 is a Schwarzschild type optical system having a numerical aperture of 0.3 to focus the mask 3 on the board 5. The entire system from the irradiating side of the illumination system to the board via the mask is installed in a liquid vessel 14, and water is fully filled in the vessel to fill the water in the optical path. Then, a pattern is transferred to a positive resist film coating the Si board by using a projection exposure apparatus to form a



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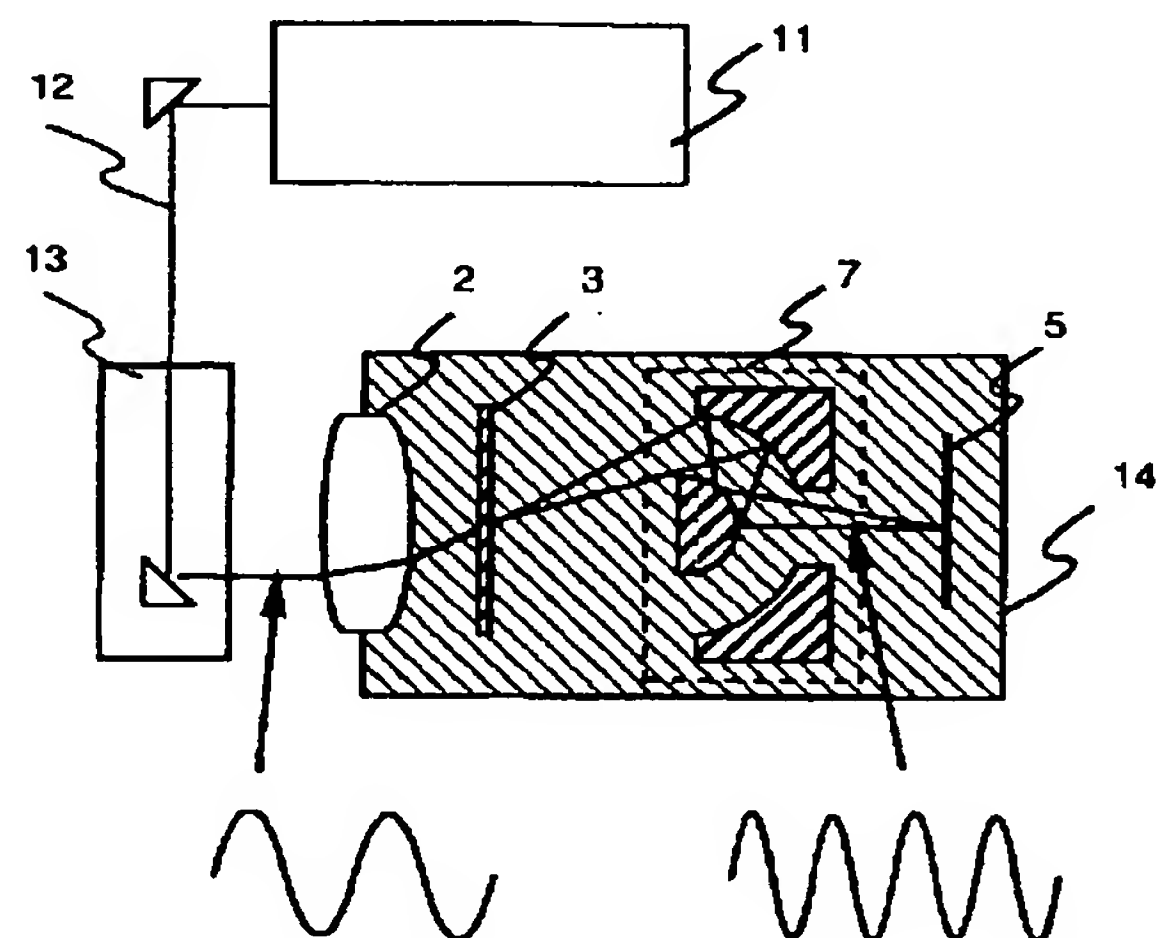
(54)【発明の名称】 パターン形成方法及びその露光装置

(57)【要約】

【構成】マスクパターン3を反射型レンズ7により基板5上へ結像させ、基板5の表面と反射型レンズ7の間を含む露光光学系の光路の全体又は一部を、露光波長における屈折率が1より大きな液体で満たす。

【効果】簡便に実効的に短波長化したのと同等の解像力向上効果を得ることができ、光リソグラフィの解像限界を30%程度向上し、0.15 μ m以下のパターンを形成することができる。

図1



【特許請求の範囲】

【請求項1】光源を発した光を照明光学系を介してマスクに照射し、上記マスク上のパターンを投影光学系により基板上へ結像させることにより上記基板上にパターンを形成する方法において、上記投影光学系を反射型レンズを含む光学系により構成し、少なくとも上記基板と上記投影光学系の間を含む上記投影光学系の光路の全体又は一部を、上記光の波長における空気に対する比屈折率が1より大きな媒質で満たすことを特徴とするパターン形成方法。

【請求項2】請求項1において、上記媒質は液体であるパターン形成方法。

【請求項3】請求項2において、上記光の波長は150～250nmであるパターン形成方法。

【請求項4】光源を発した光を照明光学系を介してマスクに照射し、上記マスク上のパターンを投影光学系により基板上へ結像させることにより上記基板上にパターンを形成する際に用いられる露光装置において、上記投影光学系を反射型レンズを含む光学系により構成し、上記基板と上記投影光学系の間を含む上記投影光学系の光路の全体又は一部を、上記光の波長における空気に対する比屈折率が1より大きな媒質で満たしたことを特徴とする投影露光装置。

【請求項5】請求項4において、上記投影光学系と前記基板の間に、透明な隔壁を設け、上記媒質を光学系側と基板側に分割する投影露光装置。

【発明の詳細な説明】

【0001】

【産業上の利用分野】本発明は、各種固体素子の微細パターンを形成するためのパターン形成方法、及びこれに用いられる投影露光装置に関する。

【0002】

【従来の技術】LSI等の固体素子の集積度及び動作速度を向上するため、回路パターンの微細化が進んでいる。現在これらのパターン形成には、量産性と解像性能に優れた縮小投影露光法が広く用いられている。

【0003】図2(b)に縮小投影露光法の光学系を模式的に示す。二次光源面上の有効光源1を発した光は照明光学系2を介してマスク3に照射され、マスク3上のパターンにより回折された光は縮小投影レンズ4により基板5上へ結像される。縮小投影レンズは通常屈折型レンズの組合せからなるものが用いられる。この方法の解像限界は露光波長に比例し、投影レンズの開口数(NA)に反比例するため、高NA化と短波長化により解像限界の向上が行われてきた。従来、露光光は、高圧水銀ランプのg線(波長436nm)、i線(波長365nm)が用いられてきたが、64メガビットDRAM以降回路寸法が光の波長より小さくなり、物理的限界に達している。

【0004】一方、顕微鏡等の光学系の実効的なNAを

増大させる方法として、液浸(油浸)法が知られている。この方法は、レンズの先端と試料の間に空気より大きな屈折率nを有する液体(通常油を用いる)を充填することにより、実効的に光の波長を $1/n$ として解像度を向上させる。この方法の、光リソグラフィへの応用は、例えば、第53回応用物理学学会学術講演会講演予稿集、第2分冊、第472頁(1992年)に論じられている。

【0005】一方、光リソグラフィ用の投影露光装置の別の形態として、ステップアンドスキャン方式等の反射型投影光学系を用いる方法が検討されている。この光学系は波長によらず最大0.7程度の大きなNAまで実現可能とされ、将来の露光装置として非常に有望である。この方式では、一部に屈折型光学素子を使用するものの色収差補正が可能なため、例えば、キセノン水銀ランプの245～253nmという比較的広い波長領域で露光を行う。このため、従来の完全屈折型光学系を用いるエキシマレーザステッパの様な精密なレーザ波長スペクトルの狭帯域化と絶対波長の安定化を必要とせず、又、多重干渉効果と定在波効果を低減することができる。又、露光面積が広いことも実用上の大きな特長となっている。

【0006】ステップアンドスキャン方式の光学系は、例えば、レジスト材料プロセス技術(技術情報協会、東京、1991年)第12頁から第14頁に論じられている。

【0007】

【発明が解決しようとする課題】ところで、上記の従来液浸法で用いられる顕微鏡等の屈折型対物レンズは、レンズ先端と試料の間に所定の屈折率の液体を充填することを前提として専用設計されたものである。この事情は投影露光用レンズの場合も同様であり、液浸対応の投影レンズは従来レンズとは全く異なる設計をもつ専用レンズとして特別に設計する必要がある。ここで、仮に液浸用以外の従来型屈折レンズの先端と基板(又は試料)の間の液体充填領域6(図2(b)斜線部分)に屈折率nの液体を充填したとする。この場合、波長は実効的に $1/n$ になるが、スネルの法則に従いレンズ先端における屈折角が減少するため、光線の光路は図2(b)の破線の様に変化して実効的なNAが減少する。このため、必ずしも解像度は向上しない。しかも、ステッパ用レンズにおいて要求される広い露光面積を、液浸レンズ特有の大きなNAと両立させるのは極めて困難であるという問題があった。

【0008】一方、光リソグラフィの解像度をさらに向上するには、露光波長をできるだけ短くすることが好ましい。しかし、従来型屈折光学系による露光法、反射型投影露光法のいずれも、光学材料の透過率の限界からArFエキシマレーザ(波長193nm)が実用的な短波長化の限界となってしまいう問題があった。

【0009】本発明の目的は、従来型の露光装置の構成

と光学系を大きく変更することなく、簡便に実効的に短波長化したのと同等の解像力向上効果を得て、広い露光領域を確保しつつ投影露光法の解像度を極限まで向上することが可能なパターン形成方法を提供することにある。

【0010】

【課題を解決するための手段】上記目的を達成するため、本発明は、光源を発した光を照明光学系を介してマスクに照射し、上記マスク上のパターンを投影光学系により基板上へ結像させることにより上記基板上にパターンを形成する方法において、上記投影光学系を反射型レンズを含む光学系により構成し、少なくとも上記基板と上記投影光学系の間を含む上記投影光学系の光路の全体又は一部を、上記光の波長における空気に対する比屈折率が1より大きな媒質で満たす。

【0011】

【作用】図2(a)に示す反射光学系の光路全体を満たす媒質の屈折率を変化させることを考える。図2(a)は、図2(b)における屈折型縮小投影レンズ4を反射型縮小投影レンズ7に置き換えたものである。図2

(a)において、媒質の屈折率が小さい場合の光線の光路と大きい場合の光線の光路を各々実線と点線で示した。反射光学系中の光路は、反射の法則に従い反射レンズの表面形状のみによって決まり、媒質の屈折率によらない。従って、媒質の屈折率を変化させても、開口数等の光学系の幾何光学的な性質は何ら変化しない。一方、媒質として真空に対する比屈折率 n の物質を用いると、波長は実効的に $1/n$ となる。この結果、実質的に波長だけが短くなったのと同じ効果が得られる。なお、図2(a)では簡単のため完全な反射光学系を仮定して説明したが、部分的には屈折光学系を用いてもよい。

【0012】また媒質は、露光波長に対する屈折率ができるだけ大きいことが望ましく、十分な解像度効果を得るために、1.2以上であることが望ましい。又、露光波長に対して実質的に透明で、かつ、光学素子及びレジストに悪影響を与えないことが望ましい。具体的には、例えば、水、又はアルコール、直鎖炭化水素等の有機溶媒、シリコン樹脂、更に無機化合物又は有機化合物をこれらに溶解した液体、又、従来液浸顕微鏡や液浸屈折率測定法等において使用されている各種液体等を用いることができる。

【0013】なお、光学系中で媒質の温度や密度等のゆらぎにより屈折率が変化すると、光学系の結像特性に悪影響を及ぼす恐れがあるため、これら温度等は注意深く制御することが望ましい。特に、走査光学系では光学系に対して基板を走査するので、媒質の流れにより結像特性が変化しないように気を付けることが好ましい。

【0014】

【実施例】

(実施例1) 本発明の一実施例による反射型投影露光装

置を図1に示す。KrFエキシマレーザ11から発生したレーザ光12を、ビーム整形光学系13及び照明光学系2を介してマスク3に照射する。マスクを通過した光は反射型縮小投影レンズ7を介して基板5を露光する。反射型縮小レンズは開口数0.3のシュバルツシュルド型光学系で、マスク3を基板5上に結像させる。但し、図中の光学系はあくまで模式的なものであり、実際の光学系の構成を忠実に示したものではない。ここで、照明光学系の射出側からマスクを経て基板に至る光学系の全体を液体容器14の内部に設置し、液体容器中に水を満たして光路を水で充填した。

【0015】次に、投影露光装置を用いて、Si基板上に塗布したポジ型レジスト膜(PMMA,膜厚 $1\mu\text{m}$)に様々な寸法のパターンを転写した結果、 $0.35\mu\text{mL/S}$ パターンを形成できた。比較のため、光学系から水を除去し空気中で露光を行ったところ解像限界は $0.5\mu\text{m}$ に後退した。

【0016】なお、露光装置の波長、光源の種類、投影レンズの方式及び開口数、媒体の種類、使用するレジストプロセス、マスクパタン寸法等、本実施例に示したものに限定しない。例えば、エキシマレーザの代わりに、高圧水銀ランプやキセノン水銀ランプを用いてもよい。又、液体溶液中に水に代えて、パーフルオロアルキルポリエーテル等を用いてもよい。この液体は、露光波長に透明であるとともにレジストの感光特性に全く影響を与えなかった。又、レジストとしても、PMMAに代えて適当なノボラック系ポジ型レジストや化学増幅系レジスト等を用いてもよい。

【0017】(実施例2) 本発明の第二の実施例による反射型投影露光装置を図3に示す。ArFエキシマレーザ(図示せず)から発生したレーザ光を、ビーム整形光学系及び照明光学系(図示せず)を介してマスク3に照射する。マスクを通過した光は走査型反射光学系21を介して基板5を露光する。走査型反射光学系は開口数0.7のステップアンドスキャン型光学系で、マスク3を基板5上に結像させる。但し、図中の光学系はあくまで模式的なものであり、実際の光学系の構成を忠実に示したものではない。ここで、投影光学系の光路内の図中斜線で示した領域22に水を充填した。

【0018】次に、投影露光装置を用いて、Si基板上に塗布したポジ型レジスト膜(PMMA,膜厚 $1\mu\text{m}$)に、様々な寸法のパターンを転写した結果、 $0.11\mu\text{mL/S}$ パターンを形成できた。比較のため、光学系から水を除去し空気中で露光を行ったところ、解像限界は $0.15\mu\text{m}$ に後退し、本発明の効果が確認された。

【0019】(実施例3) 実施例2の投影露光装置において、図4に示す様に光学系側と基板側とを石英の平行平板31により分割した。これにより、基板を光学系に対して走査したりステップ送りしたときに生じる液体媒質の流れが光学系側に及ぶことがないため、屈折率の揺

らぎ等の影響が抑えられてパターンの寸法精度が向上した。なお、石英窓挿入により発生する球面収差に対しては、あらかじめ補正を行った。

【0020】（実施例4）実施例2の投影露光装置において、図5に示す様に光学系と基板の間に石英平行平板32、33を設け、液体容器を光学系側液体容器34と基板側液体容器35に分割した。更に基板5の光学系に対する走査又はステップ送りを、基板側液体容器35ごとに行うようにした。これにより、基板近傍での液体の流れも抑制することができるため、屈折率の揺らぎ等の影

響が抑えられてパターンの寸法精度が更に向上した。

【0021】なお、本実施例による構成を実施例1に適用する場合、マスク側にも同様の機構を設けることができる。

【0022】

【発明の効果】本発明によれば、マスクパターンを投影光学系により基板上へ結像させることにより上記基板上にパターンを転写する際、投影光学系を反射型レンズを含む光学系により構成するとともに、基板表面と投影光学系の間を含む投影光学系の光路の全体又は一部を、光*

の波長における空気に対する比屈折率が1より大きな媒質で満たすことにより、従来型の露光装置の構成と光学系を大きく変更することなく、簡便に実効的に短波長化したのと同等の解像力向上を図ることができる。これにより、光リソグラフィの解像限界を30%程度向上し、 $0.15\mu\text{m}$ 以下のパターンを形成することが可能となる。

【図面の簡単な説明】

【図1】本発明の原理の説明図。

10 【図2】本発明の一実施例による露光装置の説明図。

【図3】本発明の第二の実施例による露光装置の説明図。

【図4】本発明の第三の実施例による露光装置の説明図。

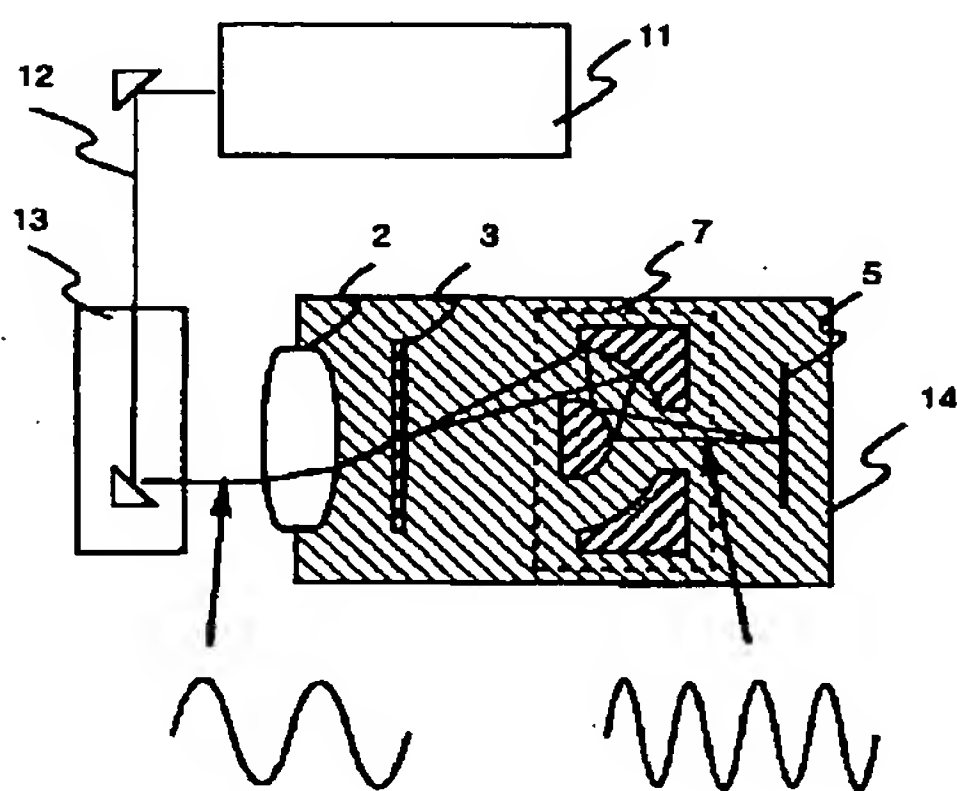
【図5】本発明の第四の実施例による露光装置の説明図。

【符号の説明】

2…照明光学系、3…マスク、5…基板、7…反射型縮小投影レンズ、11…エキシマレーザ、12…レーザ光、13…ビーム整形光学系、14…液体容器。

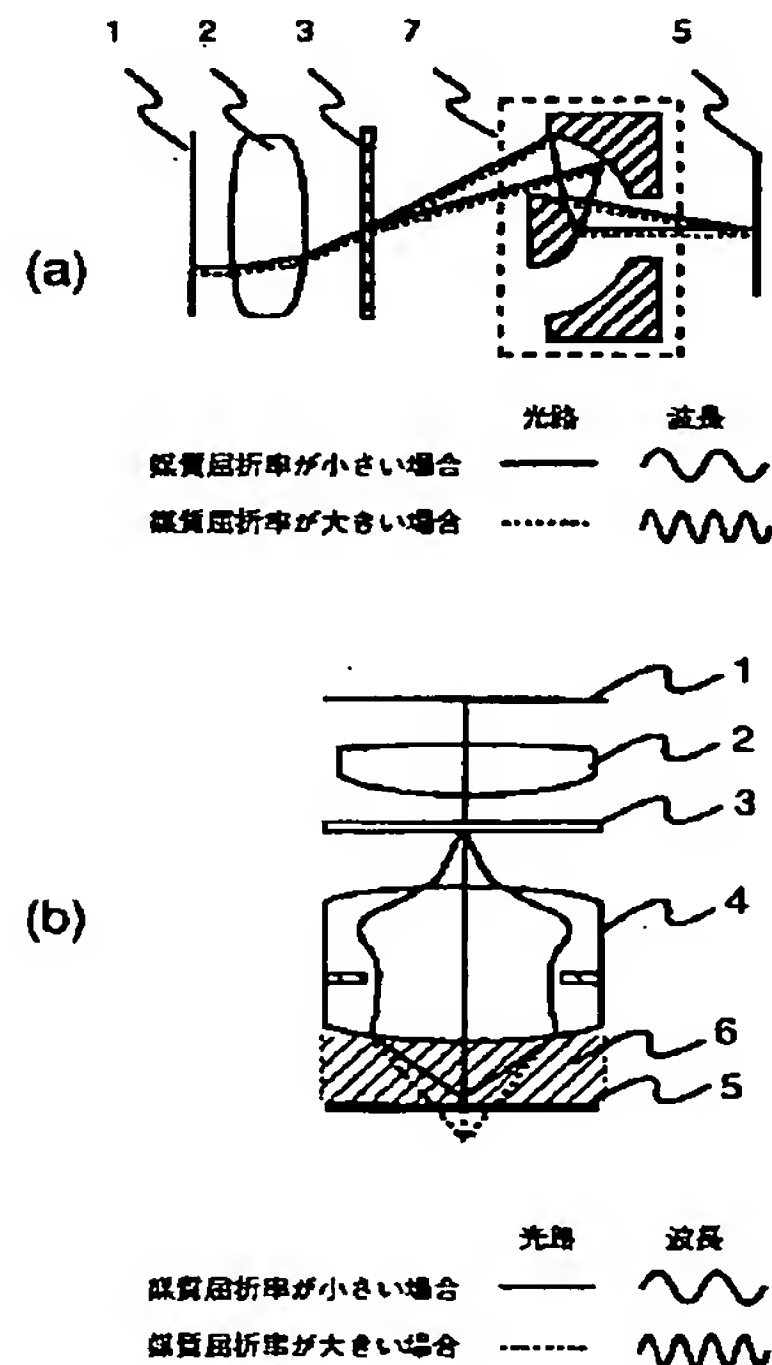
【図1】

図1



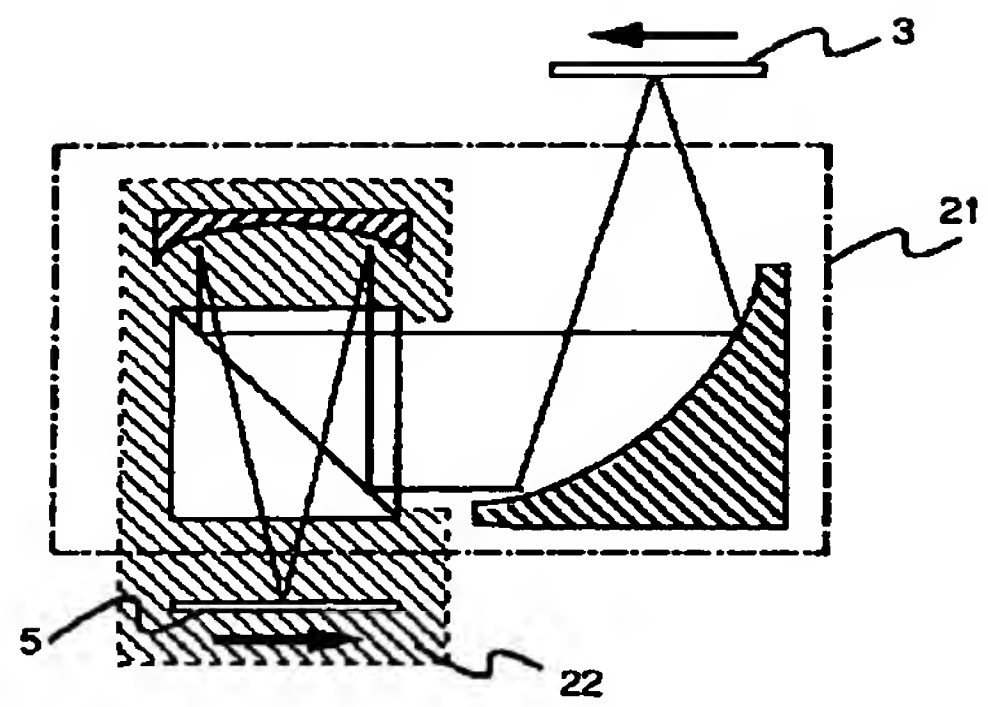
【図2】

図2



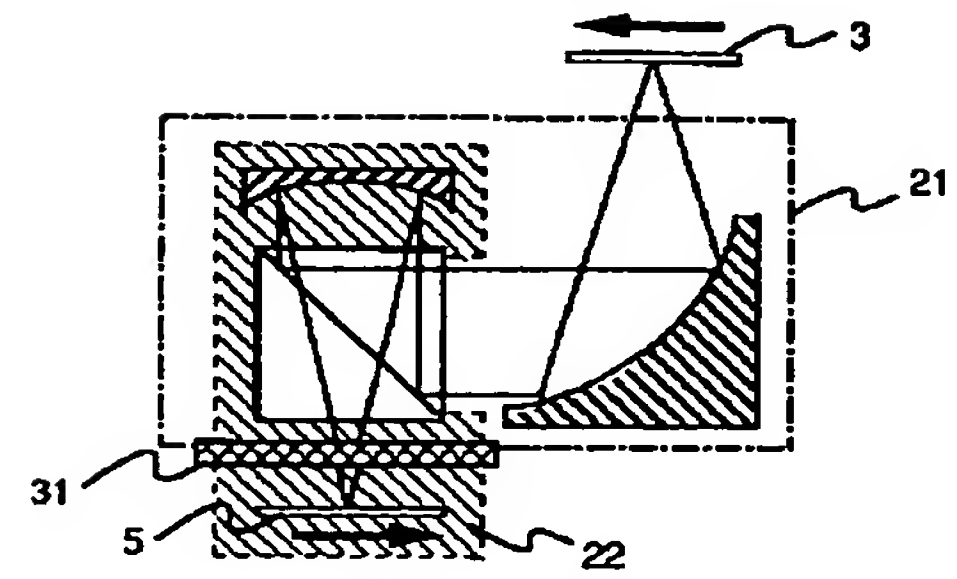
【図3】

図3



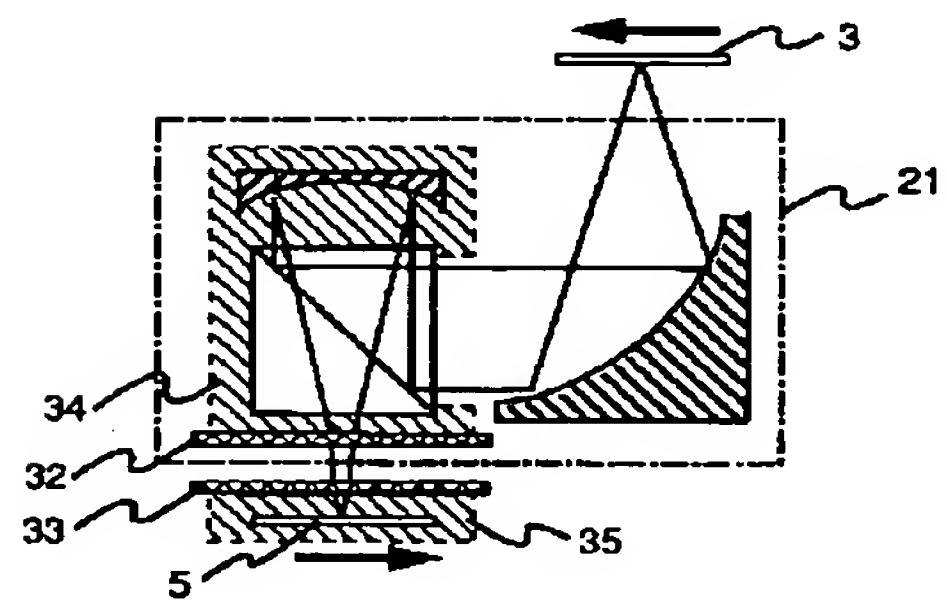
【図4】

図4



【図5】

図5



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